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- Single Chip With Easy Interface Between UART and Serial Port Connector of an External Modem or Other Computer Peripheral
- Five Drivers and Three Receivers Meet or Exceed the Requirements of ANSI EIA/TIA-232-E and ITU Recommendation V.28 Standards
- Designed to Support Data Rates Up To 120 kbps
- Complement To The GD75232
- Provides Pin-To-Pin Replacement For the Goldstar GD75323
- Pin-Out Compatible With SN75196
- Functional Replacement For the MC145405

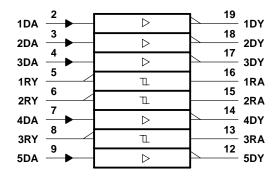
#### description

The GD75323 combines five drivers and three receivers from the trade-standard SN75188 and SN75189 bipolar quadruple drivers and receivers respectively. The flow-through design of the GD75323 decreases the part count, reduces the board space required, and allows easy interconnection of the UART and serial-port connector. The all-bipolar circuits and processing of the GD75323 provide a rugged, low-cost solution for this function.

The GD75323 complies with the requirements of the ANSI EIA/TIA-232-E and ITU (formerly CCITT) V.28 standards. These standards are for data interchange between a host computer and a peripheral at signal rates up to 20 kbps. The switching speeds of the GD75323 are fast enough to support rates up to 120 kbps with lower capacitive loads (shorter cables). Interoperability at the higher signaling rates cannot be assured unless the designer has design control of the cable and the interface circuits at both ends. For interoperability at signaling rates up to 120 kbps, use of ANSI Standard EIA/TIA-423-B and EIA/TIA-422-B and ITU Recommendations V.10 and V.11 are recommended.

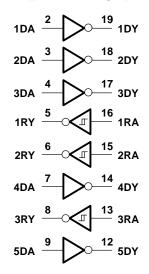
The GD75323 is characterized for operation over a temperature range of 0°C to 70°C.

logic symbol<sup>†</sup>



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

### logic diagram (positive logic)





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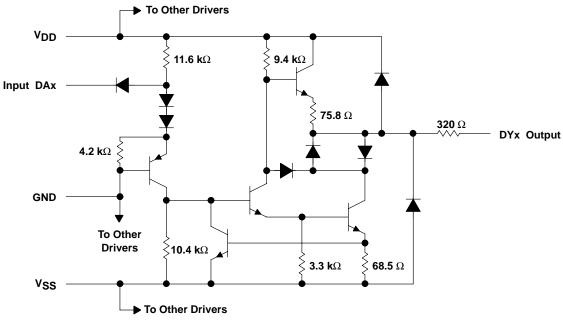
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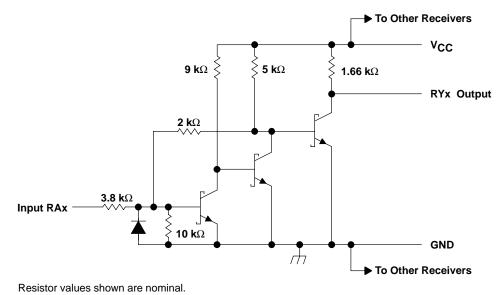
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#### schematic (each driver)



Resistor values shown are nominal.

### schematic (each receiver)





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#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage, V <sub>CC</sub> (see Note 1)	
Supply voltage, V <sub>D</sub> (see Note 1)	
Input voltage range, V <sub>I</sub> : Driver	
Receiver	30 V to 30 V
Output voltage range, V <sub>O</sub> (Driver)	– 15 V to 15 V
Low-level output current, I <sub>OL</sub> (Receiver)	20 mA
Continuous total dissipation	
Operating free-air temperature range, T <sub>A</sub>	0°C to 70°C
Storage temperature range, T <sub>stg</sub>	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltages are with respect to the network ground terminal.

#### DISSIPATION RATING TABLE

PACKAGE	T <sub>A</sub> ≤ 25°C POWER RATING	DERATING FACTOR <sup>‡</sup> ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING
DW	1125 mW	9.0 mW/°C	720 mW
N	1150 mW	9.2 mW/°C	736 mW

<sup>‡</sup> This is the inverse of the traditional junction-to-case thermal resistance ( $R_{\theta JA}$ ).

#### recommended operating conditions

		MIN	NOM	MAX	UNIT
Supply voltage, V <sub>DD</sub>		7.5	9	13.5	V
Supply voltage, VSS		-7.5	-9	-13.5	V
Supply voltage, V <sub>CC</sub>		4.5	5	5.5	V
High-level input voltage, VIH	Driver	1.9			V
Low-level input voltage, $V_{IL}$	Driver			0.8	V
High lovel output ourrent love	Driver			-6	mA
High-level output current, IOH	Receiver			-0.5	ША
High lovel output ourrent lov	Driver			6	mA
High-level output current, IOL	Receiver			16	ma
Operating free-air temperature,TA		0		70	°C



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#### supply currents over operating free-air temperature range

	PARAMETER		TEST CONDITIONS			MIN	MAX	UNIT
		All inputs at 1.9 V,	No load	V <sub>DD</sub> = 9 V,	$V_{SS} = -9 V$		25	mA
	All inputs at 1.9 v,	No load	V <sub>DD</sub> = 12 V,	$V_{SS} = -12 V$		32	ША	
'DD	Supply current from V <sub>DD</sub>	All inputs at 0.8 V,	No load	V <sub>DD</sub> = 9 V,	$V_{SS} = -9 V$		7.5	mA
	All inputs at 0.8 V; No ic	No load	$V_{DD} = 12 V,$	$V_{SS} = -12 V$		9.5	ША	
		All inputs at 1.9 V,	No load	V <sub>DD</sub> = 9 V,	$V_{SS} = -9 V$		-25	mA
100		All inputs at 1.9 v,	NO IDAU	V <sub>DD</sub> = 12 V,	$V_{SS} = -12 V$		-32	mA
ISS Supply current from VSS		No load	V <sub>DD</sub> = 9 V,	$V_{SS} = -9 V$		-5.3	mA	
		All inputs at 0.8 V, No load	V <sub>DD</sub> = 12 V,	$V_{SS} = -12 V$		-5.3	mA	
ICC	Supply current from $V_{CC}$	V <sub>DD</sub> = 5 V,	All inputs a	t 5 V,	No load		20	mA

### **DRIVER SECTION**

# electrical characteristics over operating free-air temperature range, $V_{DD}$ = 9 V, $V_{SS}$ = -9 V, $V_{CC}$ = 5 V (unless otherwise noted)

	PARAMETER		TEST CONDITIO	NS	MIN	TYP	MAX	UNIT
VOH	High-level output voltage	V <sub>IL</sub> = 0.8 V,	$R_L = 3 k\Omega$ ,	See Figure 1	6	7.5		V
VOL	Low-level output voltage (see Note 2)	V <sub>IH</sub> = 1.9 V,	$R_L = 3 k\Omega$ ,	See Figure 1		-7.5	-6	V
ΙΗ	High-level input current	V <sub>I</sub> = 5 V,	See Figure 2				10	μA
١ <sub>١L</sub>	Low-level input current	$V_{I} = 0,$	See Figure 2				-1.6	mA
IOS(H)	High-level short-circuit output current (see Note 3)	V <sub>IL</sub> = 0.8 V,	V <sub>O</sub> = 0,	See Figure 1	-4.5	-9	-19.5	mA
IOS(L)	Low-level short-circuit output current	V <sub>IH</sub> = 2 V,	$V_{O} = 0,$	See Figure 1	4.5	9	19	mA
r <sub>o</sub>	Output resistance (see Note 4)	$V_{CC} = V_{DD} = V_{CC}$	SS = 0,	$V_{O} = -2 V$ to 2 V	300			Ω

NOTES: 2. The algebraic convention, where the more positive (less negative) limit is designated as maximum, is used in this data sheet for logic levels only, e.g., if –10 V is maximum, the typical value is a more negative voltage.

3. Output short-circuit conditions must maintain the total power dissipation below absolute maximum ratings.

4. Test conditions are those specified by EIA/TIA-232-E and as listed above.

### switching characteristics, V\_{DD} = 12 V, V\_{SS} = –12 V, V\_{CC} = 5 V $\pm 10\%,$ T\_A = 25°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
<sup>t</sup> PLH	Propagation delay time, low- to high-level output	$R_L = 3 k\Omega$ to 7 k $\Omega$ , $C_L = 15 pF$ ,		315	500	ns
<sup>t</sup> PHL	Propagation delay time, high- to low-level output	See Figure 3		75	175	ns
	Transition time, low to kick level output	$\label{eq:RL} \begin{array}{ll} R_L = 3 \; k\Omega \; \text{to} \; 7 \; k\Omega, \qquad C_L = 15 \; pF, \\ \text{See Figure 3} \end{array}$		60	100	ns
<sup>t</sup> TLH	Transition time, low- to high-level output	$\label{eq:RL} \begin{array}{ll} R_L = 3 \; k \Omega \; \text{to} \; 7 \; k \Omega, \qquad C_L = 2500 \; pF, \\ \text{See Figure 3 and Note 5} \end{array}$		1.7	2.5	μs
тнь .	Transition time, high- to low-level output (see Note 5)	$\label{eq:RL} \begin{array}{ll} R_{L} = 3 \; k \Omega \; \text{to} \; 7 \; k \Omega, \qquad C_{L} = 15 \; pF, \\ \text{See Figure 3} \end{array}$		40	75	ns
		$\label{eq:RL} \begin{array}{ll} R_L = 3 \; k \Omega \; \text{to} \; 7 \; k \Omega, \qquad C_L = 2500 \; pF, \\ \text{See Figure 3 and Note 6} \end{array}$		1.5	2.5	μs

NOTES: 5. Measured between – 3-V and 3 V points of the output waveform (EIA/TIA-232-E conditions), all unused inputs are tied either high or low.

6. Measured between 3-V and -3 V points of the output waveform (EIA/TIA-232-E conditions), all unused inputs are tied either high or low.



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### **RECEIVER SECTION**

### electrical characteristics over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS			MAX	UNIT
\/	Positive-going input threshold voltage		T <sub>A</sub> = 25°C	1.75	1.9	2.3	
VIT+	Positive-going input threshold voltage	See Figure 5	$T_A = 0^{\circ}C$ to 70 $^{\circ}C$	1.55		2.3	V
$V_{IT-}$	Negative-going input threshold voltage			0.75	0.97	1.25	v
V <sub>hys</sub>	Input hysteresis voltage (V <sub>IT+</sub> – V <sub>IT</sub> _)	See Figure 5		0.5			
V		1au 0.5 mA	V <sub>IH</sub> = 0.75 V	2.6	4	5	V
VOH	High-level output voltage	I <sub>OH</sub> = -0.5 mA	Inputs open	2.6			v
VOL	Low-level output voltage	I <sub>OL</sub> = 10 mA,	V <sub>I</sub> = 3 V		0.2	0.45	V
1	High-level input current	V <sub>I</sub> = 25 V,	See Figure 5	3.6		8.3	mA
IН	High-level input current	V <sub>I</sub> = 3 V,	See Figure 5	0.43			
1		V <sub>I</sub> = -25 V,	See Figure 5	-3.6		-8.3	~^^
l'IL	Low-level input current	$V_{I} = -3 V_{,}$	See Figure 5	-0.43			mA
los	Short-circuit output current	See Figure 4			-3.4	-12	mA

<sup>†</sup> All typical values are at  $T_A = 25^{\circ}C$ ,  $V_{CC} = 5$  V,  $V_{DD} = 9$  V, and  $V_{SS} = -9$  V.

### switching characteristics, V\_{CC} = 5 V, V\_{DD} = 12 V, V\_{SS} = -12 V, T\_A = 25^{\circ}C

PARAMETER		TEST CO	MIN	TYP	MAX	UNIT	
<sup>t</sup> PLH	Propagation delay time, low- to high-level output				107	500	ns
<sup>t</sup> PHL	Propagation delay time, high- to low-level output	C <sub>L</sub> = 50 pF,	$R_L = 5 k\Omega$ ,		42	150	ns
<sup>t</sup> TLH	Transition time, low- to high-level output	See Figure 6			175	525	ns
<sup>t</sup> THL	Transition time, high- to low-level output				16	60	ns

### PARAMETER MEASUREMENT INFORMATION

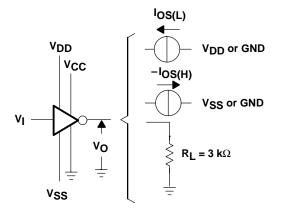


Figure 1. Driver Test Circuit for V\_OH, V\_OL, I\_OS(H), and I\_OS(L)

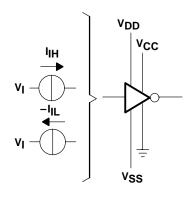


Figure 2. Driver Test Circuit for  $I_{IH}$  and  $I_{IL}$ 



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#### PARAMETER MEASUREMENT INFORMATION

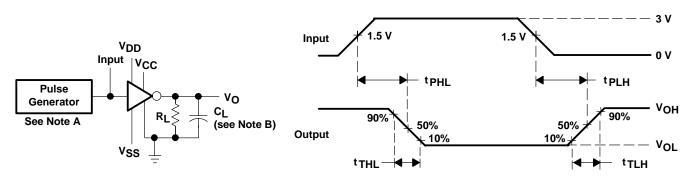


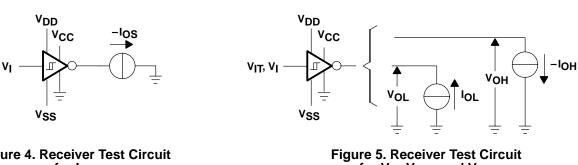
Figure 3. Driver Test Circuit and Voltage Waveforms

#### **TEST CIRCUIT**

**VOLTAGE WAVEFORMS** 

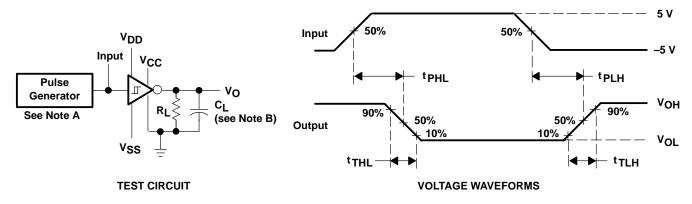
NOTES: A. The pulse generator has the following characteristics:  $t_W = 25 \mu s$ , PRR = 20 kHz,  $Z_O = 50 \Omega$ ,  $t_T = t_f < 50 ns$ .

B. CL includes probe and jig capacitance.





for VIT, VOH, and VOL



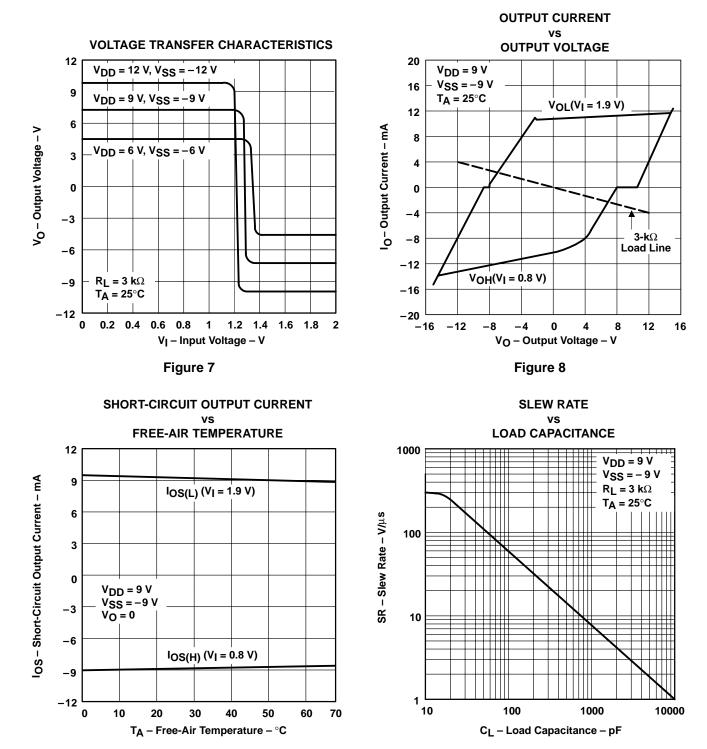
NOTES: A. The pulse generator has the following characteristics:  $t_w = 25 \mu s$ , PRR = 20 kHz,  $Z_O = 50 \Omega$ ,  $t_r = t_f < 50 ns$ . B. CL includes probe and jig capacitance.

#### Figure 6. Receiver Propagation and Transition Times



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### **TYPICAL CHARACTERISTICS**



**DRIVER SECTION** 

Figure 10

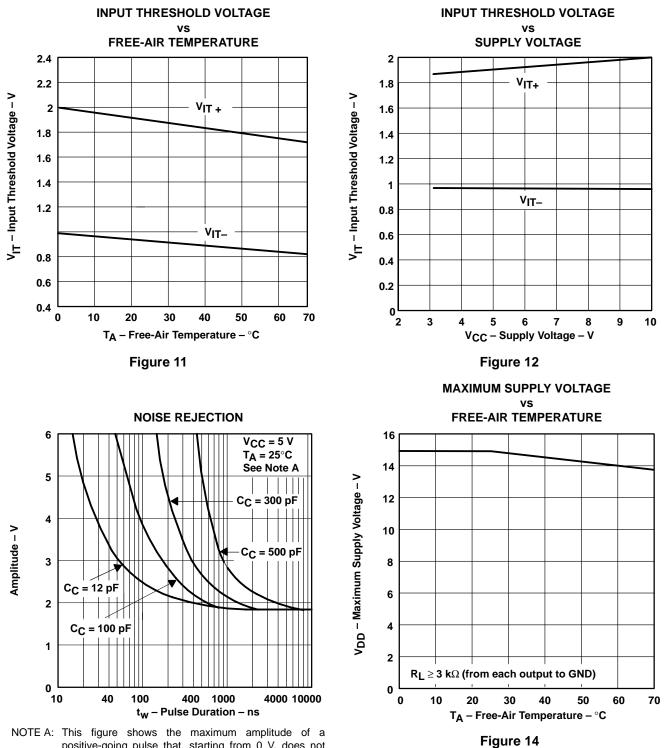


Figure 9

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### **TYPICAL CHARACTERISTICS**

### **RECEIVER SECTION**



positive-going pulse that, starting from 0 V, does not cause a change of the output level.

Figure 13



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### **APPLICATION INFORMATION**

Diodes placed in series with the  $V_{DD}$  and  $V_{SS}$  leads protect the GD75323 in the fault condition in which the device outputs are shorted to  $V_{DD}$  or  $V_{SS}$ , and the power supplies are at low and provide low-impedance paths to ground (see Figure 15).

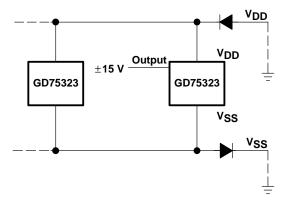
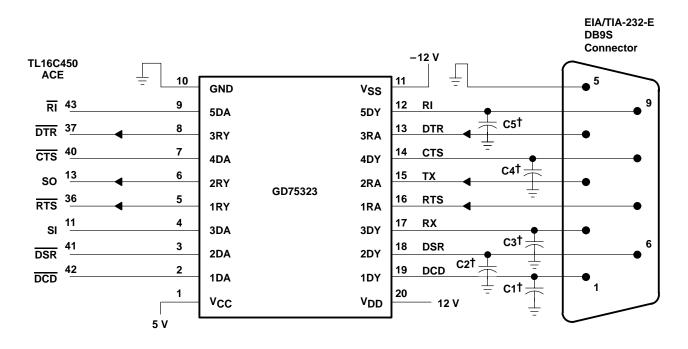


Figure 15. Power-Supply Protection to Meet Power-Off Fault Conditions of EIA/TIA-232-E



<sup>+</sup> See Figure 10 to select the correct values for the loading capacitors (C1, C2, C3, C4, and C5), which may be required to meet the RS-232 maximum slew-rate requirement of 30 V/μs. The value of the loading capacitors required depends upon the line length and desired slew rate, but is typically 330 pF.

NOTE C: To use the receivers only, V<sub>DD</sub> and V<sub>SS</sub> must both be powered or tied to ground.

Figure 16. Typical Connection



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